

BT137X-800E 4Q Triac

Rev.01 - 19 April 2018

Product data sheet

1. General description

Planar passivated sensitive gate four quadrant triac in a SOT186A (TO-220F) plastic package intended for use in general purpose bidirectional switching and phase control applications. This sensitive gate "series E" triac is intended to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

2. Features and benefits

- High blocking voltage capability
- Planar passivated for voltage ruggedness and reliability
- · Low holding current for small load currents and lowest EMI at commutation
- Triggering in all four quadrants
- Isolated package
- Direct triggering from low power drivers and logic ICs
- Sensitive gate

3. Applications

- General purpose motor control
- General purpose switching

4. Quick reference data

Symbol	Parameter	Conditions		Va	luce		Unit
Symbol		Conditions	Values				
Absolute	maximum rating						
V_{DRM}	repetitive peak off-state voltage			8	300		V
$I_{T(RMS)}$	RMS on-state current	full sine wave; T _h ≤ 73 °C; <u>Fig. 1; Fig. 2</u> ; <u>Fig. 3</u>	8		A		
I _{TSM}	non-repetitive peak on- state current	full sine wave; T _{j(init)} = 25 °C; t _p = 20 ms; <u>Fig. 4</u> ; <u>Fig. 5</u>	65		A		
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static ch	aracteristics						
I _{GT}	gate trigger current	V _D = 12 V; I _T = 0.1 A; T2+ G+; T _j = 25 °C; <u>Fig. 7</u>		-	2.5	10	mA
		V _D = 12 V; I _T = 0.1 A; T2+ G-; T _j = 25 °C; <u>Fig. 7</u>		-	4	10	mA
		V _D = 12 V; I _T = 0.1 A; T2- G-; T _j = 25 °C; <u>Fig. 7</u>		-	5	10	mA
		V _D = 12 V; I _T = 0.1 A; T2- G+; T _i = 25 °C; <u>Fig. 7</u>		-	11	25	mA

5. Pinning information

T2 T1 G
T2-T1 G
T2 T1 G
sym051

6. Ordering information

Table 3. Ordering information							
Type number	Package						
	Name	Description	Version				
BT137X-800E	TO-220F	plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220 "full pack"	SOT186A				

7. Marking

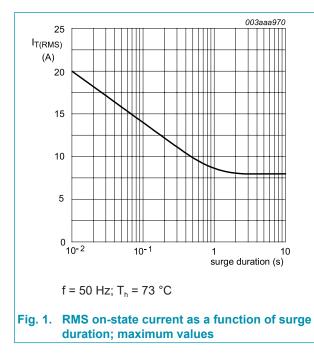
Table 4. Marking codes						
Type number	Marking codes					
BT137X-800E	BT137X-800E					

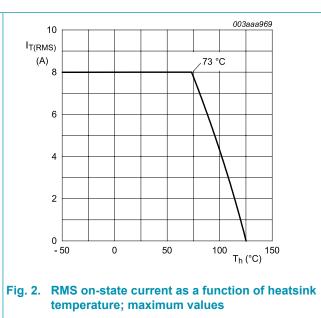
8. Limiting values

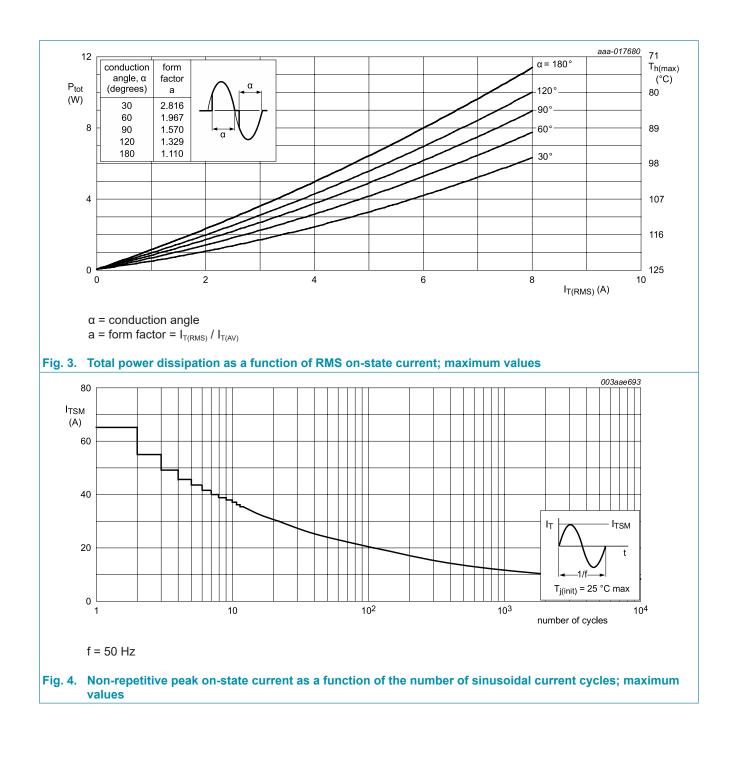
Table 5. Limiting values

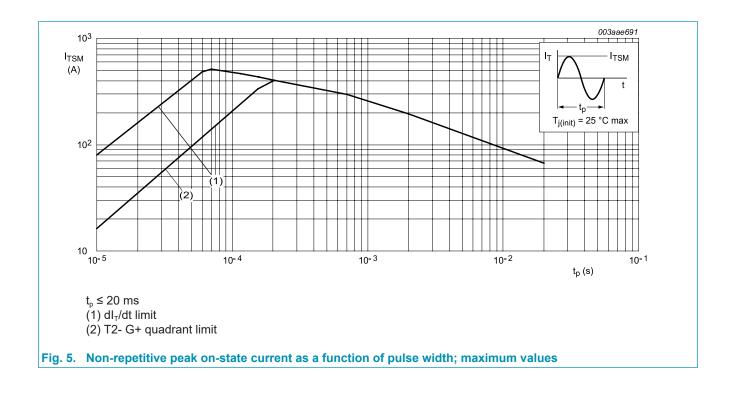
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Values	Unit
V_{DRM}	repetitive peak off-state voltage		800	V
I _{T(RMS)}	RMS on-state current	full sine wave; T _h ≤ 73 °C; <u>Fig 1</u> ; <u>Fig 2</u> ; <u>Fig 3</u>	8	A
I _{TSM}	non-repetitive peak on- state current	full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig 4; Fig 5	65	A
		full sine wave; $T_{j(init)}$ = 25 °C; t_p = 16.7 ms	71	А
l ² t	I ² t for fusing	t _p = 10 ms; SIN	21	A ² s
dl _T /dt	rate of rise of on-state current	I _G = 20 mA; T2+ G+	50	A/µs
		I _G = 20 mA; T2+ G-	50	A/µs
		I _G = 20 mA; T2- G-	50	A/µs
		I _G = 50 mA; T2- G+	10	A/µs
I _{GM}	peak gate current		2	А
P_{GM}	peak gate power		5	W
$P_{G(AV)}$	average gate power	over any 20 ms period	0.5	W
T _{stg}	storage temperature		-40 to 150	°C
Tj	junction temperature		125	°C



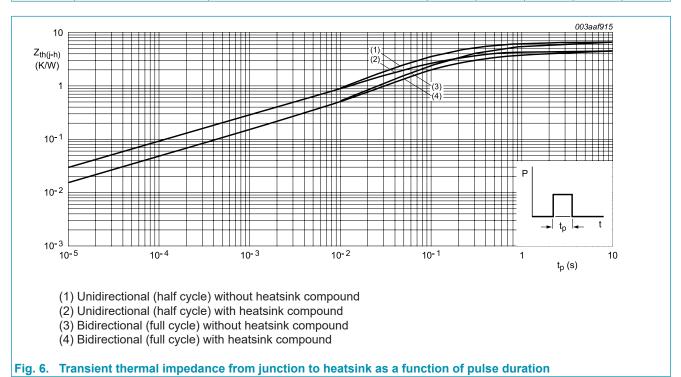






9. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-h)}$	thermal resistance from junction to heatsink	full or half cycle; with heatsink compound; Fig 6	-	-	4.5	K/W
		full or half cycle; without heatsink compound; <u>Fig 6</u>	-	-	6.5	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient	in free air	-	55	-	K/W



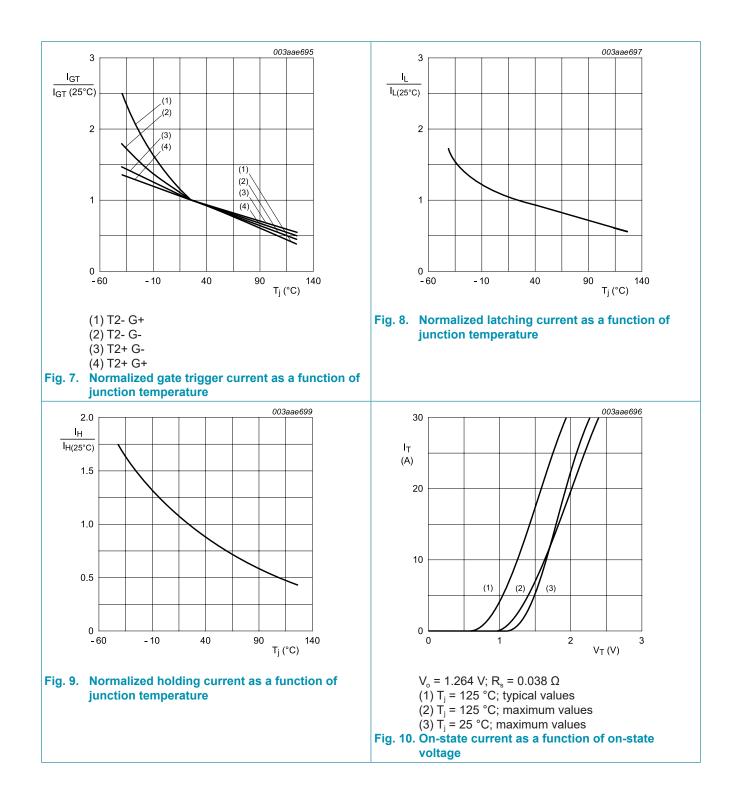
10. Isolation characteristics

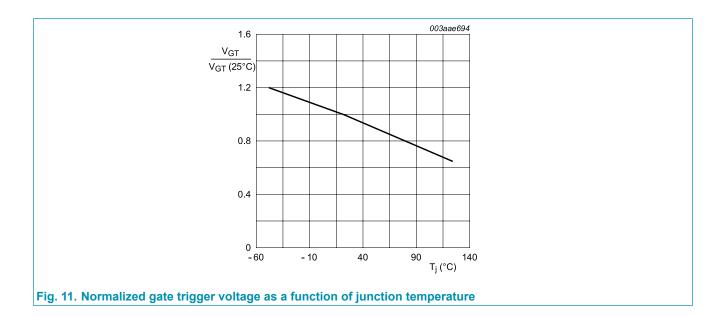
Table 7. Isolation characteristics

	nation characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{isol(RMS)}	RMS isolation voltage	from all terminals to external heatsink; sinusoidal waveform; clean and dust free; 50 Hz \leq f \leq 60 Hz; RH \leq 65 %; T _h = 25 °C	-	-	2500	V
C _{isol}	isolation capacitance	from main terminal 2 to external heatsink; f = 1 MHz; $T_h = 25 ^{\circ}\text{C}$	-	10	-	pF

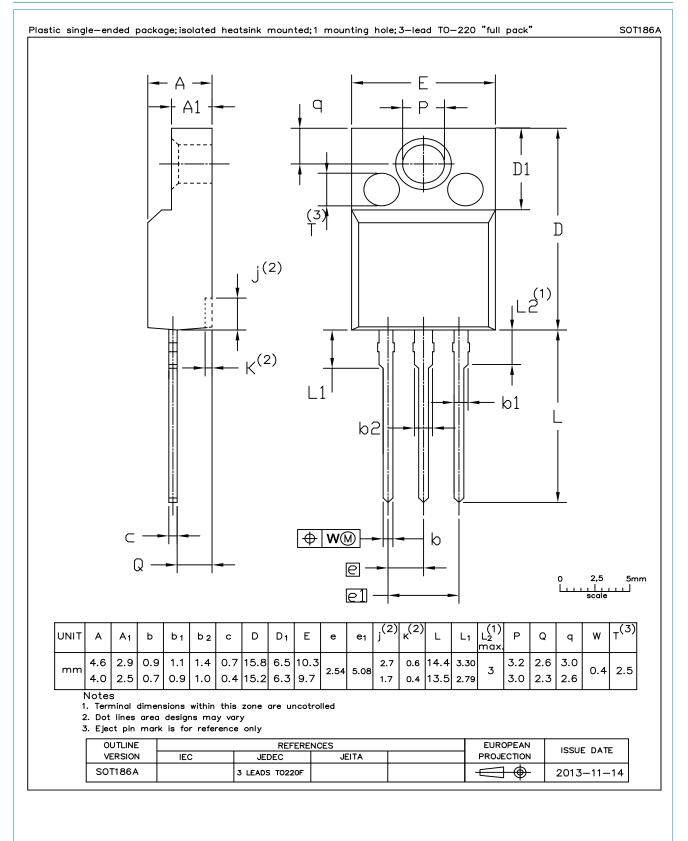
11. Characteristics

	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$		aracteristics					
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Ι _{GT}	gate trigger current		-	2.5	10	mA
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$				-	4	10	mA
$ \begin{array}{ c c c c c c c } T_{j}^{-} = 25 \ ^{\circ}\text{C}; \ \overrightarrow{\text{Fig. }T} & & & & & & & & & & & & & & & & & &$				-	5	10	mA
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$				-	11	25	mA
$ \begin{array}{ c c c c c c c c } \hline \mbox{T}_{j} = 25 \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ $	l.	latching current		-	3	25	mA
$ \begin{array}{ c c c c c c c c } \hline T_j = 25 \ ^{\circ}\text{C}; \ \overline{\text{Fig. 8}} & & & & & & & & & & & & & & & & & &$				-	14	35	mA
$\begin{array}{ c c c c c c c c } \hline T_{j} = 25 \ ^{\circ}\text{C}; \ \hline \text{Fig. 8} & & & & & & & & & & & \\ \hline I_{H} & \text{holding current} & V_{D} = 12 \ V; \ T_{j} = 25 \ ^{\circ}\text{C}; \ \hline \text{Fig. 9} & & - & 2.5 & 20 & \\ \hline V_{T} & \text{on-state voltage} & I_{T} = 10 \ \text{A}; \ T_{j} = 25 \ ^{\circ}\text{C}; \ \hline \text{Fig. 10} & & - & 1.3 & 1.65 & \\ \hline V_{GT} & & & & & & \\ \hline gate \ trigger \ voltage & & & & & \\ \hline V_{D} = 12 \ V; \ I_{T} = 0.1 \ \text{A}; \ T_{j} = 25 \ ^{\circ}\text{C}; & & & & - & 0.7 & 1 & \\ \hline V_{D} = 400 \ V; \ I_{T} = 0.1 \ \text{A}; \ T_{j} = 125 \ ^{\circ}\text{C}; & & & & & \\ \hline V_{D} = 400 \ V; \ I_{T} = 0.1 \ \text{A}; \ T_{j} = 125 \ ^{\circ}\text{C}; & & & & & \\ \hline V_{D} = 400 \ V; \ I_{T} = 0.1 \ \text{A}; \ T_{j} = 125 \ ^{\circ}\text{C}; & & & & & & \\ \hline 0.25 & 0.4 & - & & & \\ \hline I_{D} & & & & & & \\ \hline Oynamic \ characteristics & & & & \\ \hline Oynamic \ characteristics & & & & \\ \hline Oynamic \ characteristics & & & \\ \hline dV_{D}/dt & & \ rate \ of \ rise \ of \ off-state \ voltage & & & \\ \hline V_{DM} = 536 \ V; \ T_{j} = 125 \ ^{\circ}\text{C}; \ (V_{DM} = 67\% & & & & & \\ \hline oynamic \ voltage & & & & \\ \hline Oynem, \ is \ exponential \ waveform; \ gate \ open \ circuit & & \\ \hline t_{gt} & & & \\ \hline gate-controlled \ turn-on & & & \\ \hline V_{D} = 800 \ V; \ I_{TM} = 12 \ \text{A}; \ I_{G} = 0.1 \ \text{A}; & & & & & \\ \hline \end{array}$				-	3	25	mA
V _T on-state voltage I _T = 10 A; T _j = 25 °C; Fig. 10 - 1.3 1.65 V _{GT} gate trigger voltage V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; Fig. 11 - 0.7 1 V _D = 400 V; I _T = 0.1 A; T _j = 125 °C; Fig. 11 0.25 0.4 - V _D = 400 V; I _T = 0.1 A; T _j = 125 °C; Fig. 11 0.25 0.4 - V _D = 400 V; I _T = 125 °C - 0.1 0.5 Dynamic characteristics V _D = 800 V; T _j = 125 °C; (V _{DM} = 67% of V _{DRM}); exponential waveform; gate open circuit - 50 - t _{gt} gate-controlled turn-on V _D = 800 V; I _T = 12 A; I _G = 0.1 A; - 2 -				-	4	35	mA
VGT gate trigger voltage $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 ^{\circ}\text{C};$ Fig. 11 - 0.7 1 $V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 ^{\circ}\text{C};$ Fig. 11 0.25 0.4 - $V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 ^{\circ}\text{C};$ 0.25 0.4 - I_D off-state current $V_D = 800 \text{ V}; T_j = 125 ^{\circ}\text{C}$ - 0.1 0.5 Dynamic characteristics $V_{DM} = 536 \text{ V}; T_j = 125 ^{\circ}\text{C}; (V_{DM} = 67\%) \text{ of } V_{DRM}; exponential waveform; gate open circuit - 50 - t_{gt} gate-controlled turn-on V_D = 800 \text{ V}; I_T = 12 \text{ A}; I_G = 0.1 \text{ A}; - 2 - $	I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	2.5	20	mA
Fig. 11 Image: Sector of the state current Fig. 11 Image: Sector of the state current V_D = 400 V; I_T = 0.1 A; T_J = 125 °C; T_J = 125 °C; C; C; T_J = 125 °C; C 0.25 0.4 - I_D off-state current V_D = 800 V; T_J = 125 °C; C - 0.1 0.5 Opnamic characteristics V_D = 536 V; T_J = 125 °C; (V_DM = 67% of V_DRM); exponential waveform; gate open circuit - 50 - t_gt gate-controlled turn-on V_D = 800 V; I_TM = 12 A; I_G = 0.1 A; - 2 -	V _T	on-state voltage	I _T = 10 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.3	1.65	V
Fig. 11Fig. 11III_Doff-state current $V_D = 800 \text{ V}; \text{ T}_j = 125 \text{ °C}$ -0.10.5Opnamic characteristics dV_D/dt rate of rise of off-state voltage $V_{DM} = 536 \text{ V}; \text{ T}_j = 125 \text{ °C}; (V_{DM} = 67\%)of V_{DRM}; exponential waveform; gateopen circuit-50-t_{gt}gate-controlled turn-onV_D = 800 \text{ V}; \text{ I}_{TM} = 12 \text{ A}; \text{ I}_G = 0.1 \text{ A};-2-$	V _{GT}	gate trigger voltage		-	0.7	1	V
Dynamic characteristics dV_D/dt rate of rise of off-state voltage $V_{DM} = 536 \text{ V}; \text{ T}_j = 125 \text{ °C}; (V_{DM} = 67\%)of V_{DRM}; exponential waveform; gateopen circuit-50-t_{gt}gate-controlled turn-onV_D = 800 \text{ V}; \text{ I}_T = 12 \text{ A}; \text{ I}_G = 0.1 \text{ A};-2-$				0.25	0.4	-	V
$\frac{dV_{D}}{dt} rate of rise of off-state voltage V_{DM} = 536 \text{ V}; \text{T}_{\text{j}} = 125 ^{\circ}\text{C}; (V_{DM} = 67\% $	I _D	off-state current	V _D = 800 V; T _j = 125 °C	-	0.1	0.5	mA
voltageof V_{DRM}); exponential waveform; gate open circuit-2 t_{gt} gate-controlled turn-on $V_D = 800 \text{ V}$; $I_{TM} = 12 \text{ A}$; $I_G = 0.1 \text{ A}$;-2	Dynamic	characteristics			_		
	dV _D /dt		of V _{DRM}); exponential waveform; gate	-	50	-	V/µs
ume di _G /dt – 5 A/µs	t _{gt}	gate-controlled turn-on time	$V_{\rm D}$ = 800 V; I _{TM} = 12 A; I _G = 0.1 A; dI _G /dt = 5 A/µs	-	2	-	μs





12. Package outline



13. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

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